

Notice of References Cited

Application/Control No.

10/022,150

Applicant(s)/Patent Under
Reexamination
FEWSTER ET AL.

Examiner

Allen C. Ho

Art Unit

2882

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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	F	US-			
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FOREIGN PATENT DOCUMENTS

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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	B. D. Cullity. Elements of X-Ray Diffraction, second edition (Reading, MA: Addison-Wesley, 1978), p. 188-196.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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